

Notice of References Cited		Application/Control No. 10/577,325	Applicant(s)/Patent Under Reexamination NAKAMURA ET AL.	
		Examiner MATTHEW W. SUCH	Art Unit 2891	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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NON-PATENT DOCUMENTS

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*	U	Klauk, H., et al. "Contact Resistance in Organic Thin Film Transistors." SOLID-STATE ELECTRONICS, Vol. 47 (2003): pp. 297-301.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.